Most Frequently Occurring Classifications of Patents Returned
From A Search of 10063787 on June 01, 2006


Original Classifications
   2   73/626

Cross-Reference Classifications
   2   706/45
   2   714/735
   2   714/736
   2   714/738
   2   714/741

Combined Classifications
   3   706/45
   2    73/626
   2   324/158.1
   2   324/73.1
   2   714/724
   2   714/726
   2   714/735
   2   714/736
   2   714/738
   2   714/741
   2   714/820

10063787_CLSTITLES1.txt
Titles of Most Frequently Occurring Classifications of Patents Returned
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3  706/45       (1 OR, 2 XR)
       Class   706 :  DATA PROCESSING: ARTIFICIAL INTELLIGENCE
       706/45          KNOWLEDGE PROCESSING SYSTEM

2  73/626       (2 OR, 0 XR)
       Class   073 :  MEASURING AND TESTING
       73/570          VIBRATION
       73/584          .By mechanical waves
       73/596          ..Beamed
       73/618          ...Measuring or testing system having scanning
                          means
       73/620          ....By reflected wave
       73/625          .....Having plural sonic type transmitter or
                          receiver transducers
       73/626          ......Switched

2  324/158.1    (1 OR, 1 XR)
       Class   324 :  ELECTRICITY:  MEASURING AND TESTING
       324/158.1       MISCELLANEOUS

2  324/73.1     (1 OR, 1 XR)
       Class   324 :  ELECTRICITY:  MEASURING AND TESTING
       324/73.1         PLURAL, AUTOMATICALLY SEQUENTIAL TESTS

2  714/724      (1 OR, 1 XR)
       Class   714 :  ERROR DETECTION/CORRECTION AND FAULT
                          DETECTION/RECOVERY
       714/699          PULSE OR DATA ERROR HANDLING
       714/724          .Digital logic testing

2  714/726      (1 OR, 1 XR)
       Class   714 :  ERROR DETECTION/CORRECTION AND FAULT
                          DETECTION/RECOVERY
       714/699          PULSE OR DATA ERROR HANDLING
       714/724          .Digital logic testing
       714/726          ..Scan path testing (e.g., level sensitive scan
                          design (LSSD))

2  714/735      (0 OR, 2 XR)
       Class   714 :  ERROR DETECTION/CORRECTION AND FAULT
                          DETECTION/RECOVERY
       714/699          PULSE OR DATA ERROR HANDLING
       714/724          .Digital logic testing
       714/735          ..Device response compared to input pattern

2  714/736      (0 OR, 2 XR)
       Class   714 :  ERROR DETECTION/CORRECTION AND FAULT
                          DETECTION/RECOVERY
       714/699          PULSE OR DATA ERROR HANDLING
       714/724          .Digital logic testing
       714/736          ..Device response compared to expected
                          fault-free response

2  714/738      (0 OR, 2 XR)
       Class   714 :  ERROR DETECTION/CORRECTION AND FAULT
                          DETECTION/RECOVERY
       714/699          PULSE OR DATA ERROR HANDLING
       714/724          .Digital logic testing
       714/738          ..Including test pattern generator
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2  714/741      (0 OR, 2 XR)
       Class    714 :  ERROR DETECTION/CORRECTION AND FAULT
                          DETECTION/RECOVERY
       714/699          PULSE OR DATA ERROR HANDLING
       714/724          .Digital logic testing
       714/738          ..Including test pattern generator
       714/741          ...Simulation

2  714/820      (1 OR, 1 XR)
       Class    714 :  ERROR DETECTION/CORRECTION AND FAULT
                          DETECTION/RECOVERY
       714/699          PULSE OR DATA ERROR HANDLING
       714/799          .Error/fault detection technique
       714/819          ..Comparison of data
       714/820          ...Plural parallel devices of channels
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